

A New Real-Time Quantum Efficiency Measurement System

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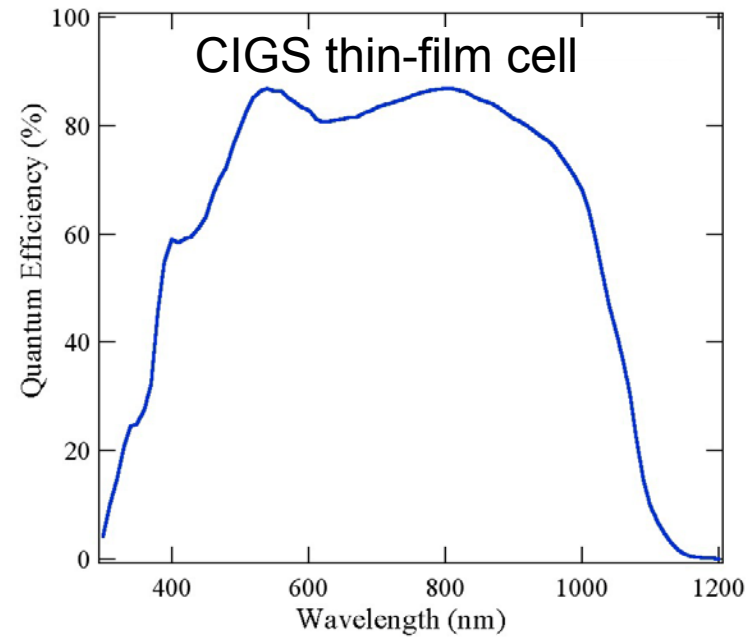
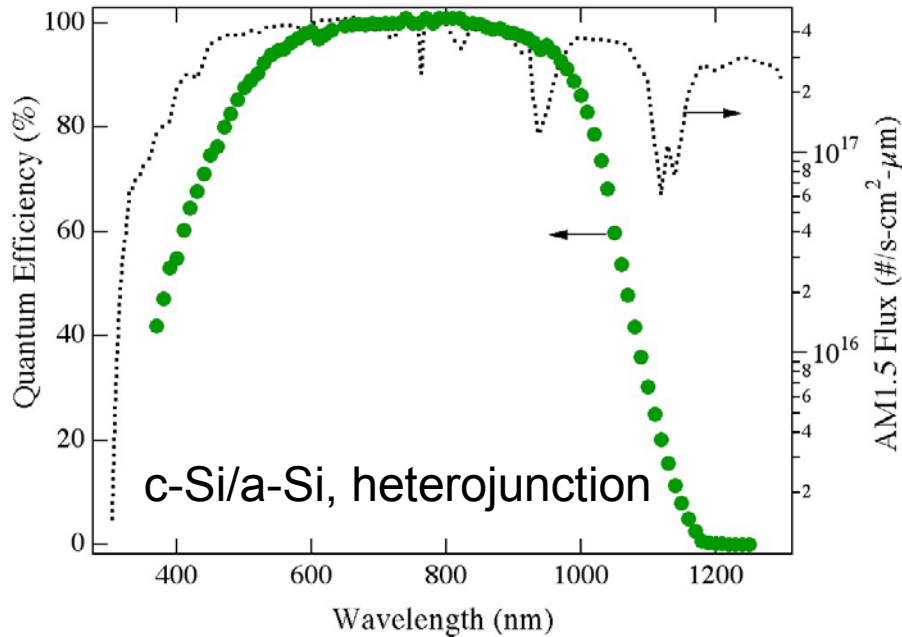
² Colorado School of Mines, Golden, Colorado 80401 (USA)

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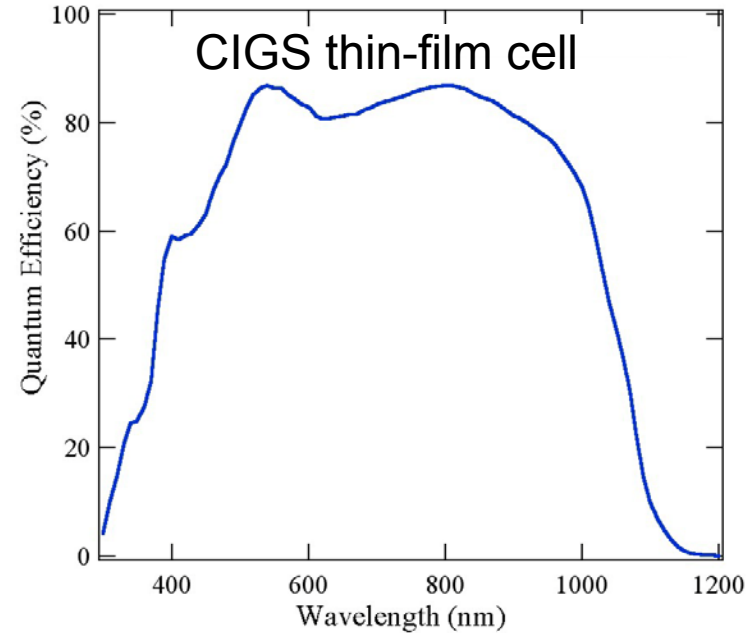
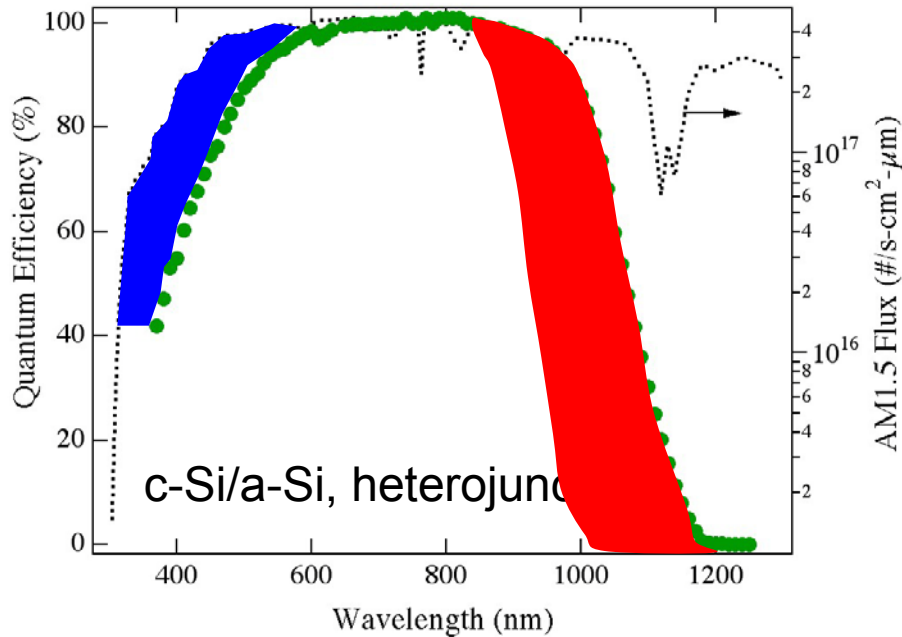


Information-Rich Quantum Efficiency Graphs



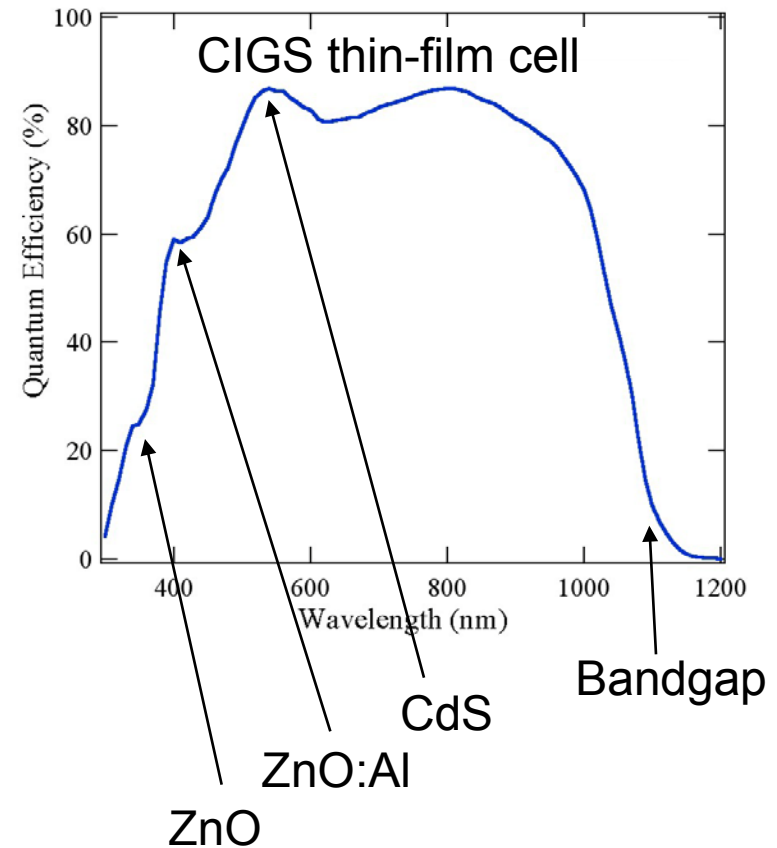
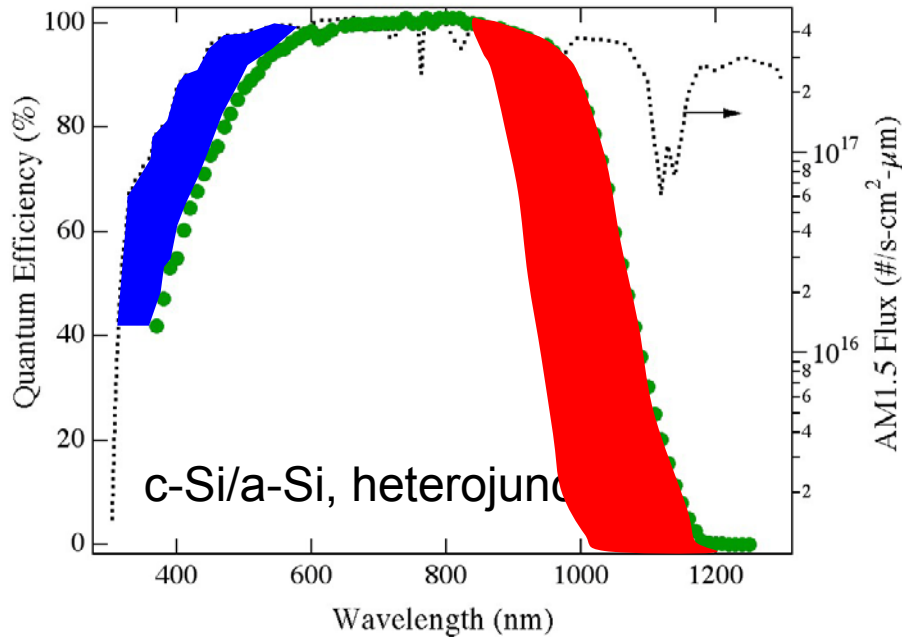
- Spectral response (current loss)
- Spatial response
 - “Blue” – front, “Red” - back surfaces, bulk
 - thin-film layers (thickness, composition, Bandgap)
- Diffusion length (modeling) (Kieliba, JAP 2006)
- Recombination centers (QE(T)) (Wagner, APL 2003)
- Junction physics, impurity diffusion (QE(V)) (Batzner TSF 2003), (a-Si:H cells)

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Information-Rich Quantum Efficiency Graphs

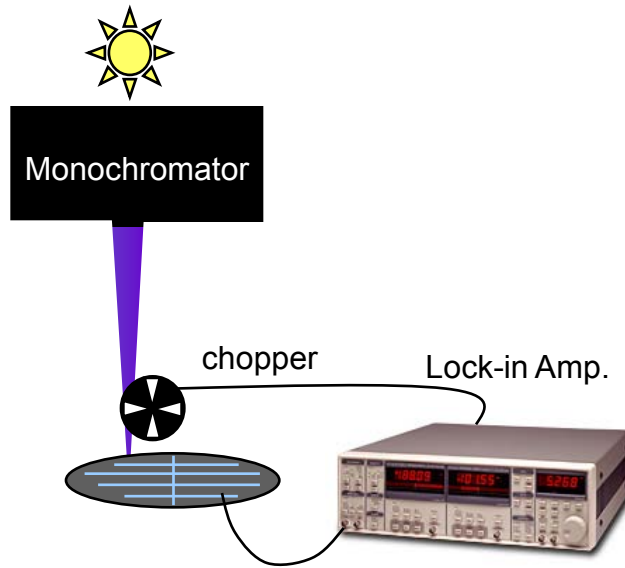


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So, why don't we use QE graphs more in research and industry?

Traditional QE method

Time! (money, lack of graduate students)



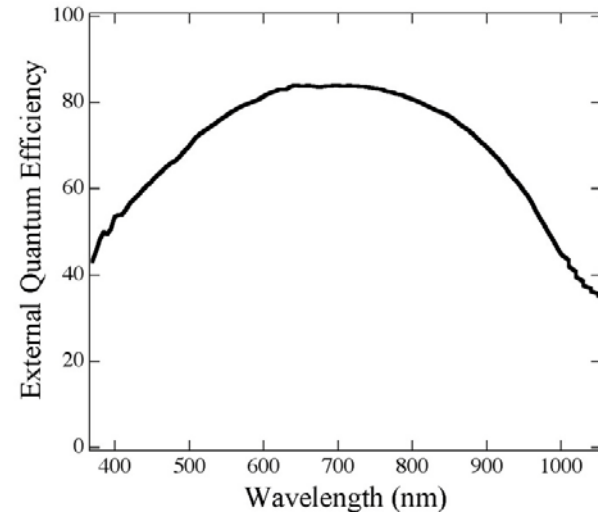
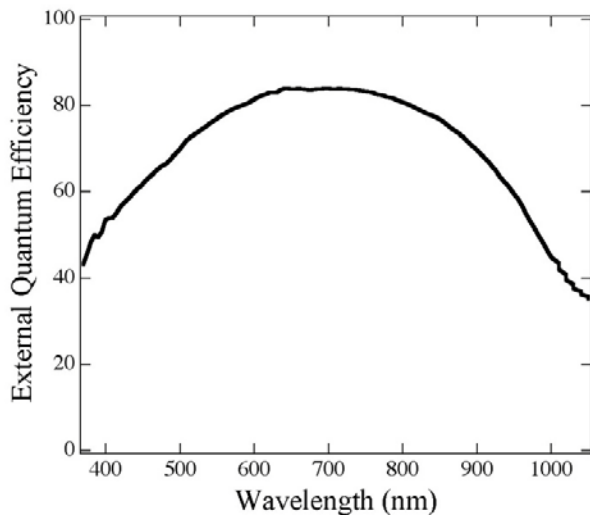
New method

Electronically-controlled light source



Parallel measurement ~ 0.1 sec

Serial measurement ~ 5-20 mins

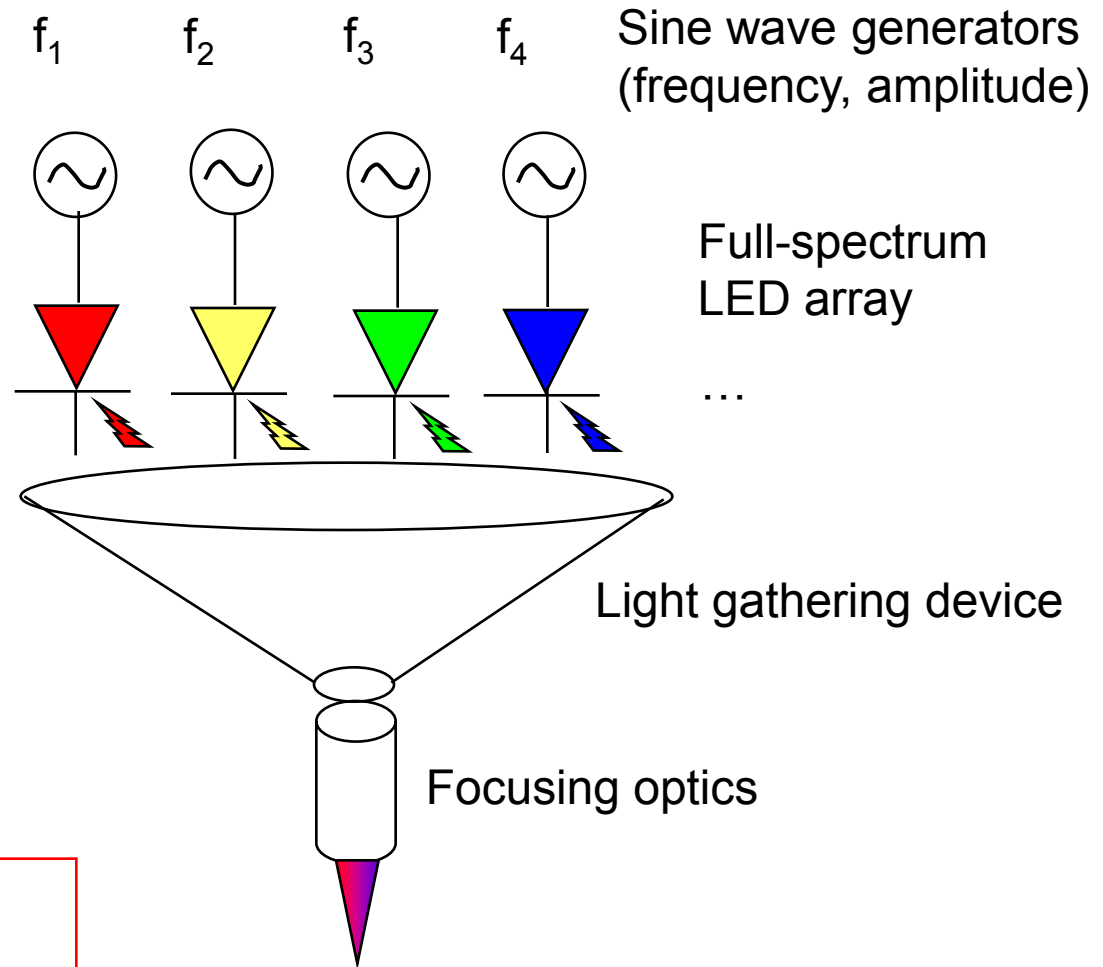


1000x decrease in time

New method: Real –Time Quantum Efficiency measurement system (RTQE)

Electronically-Controlled LED light source

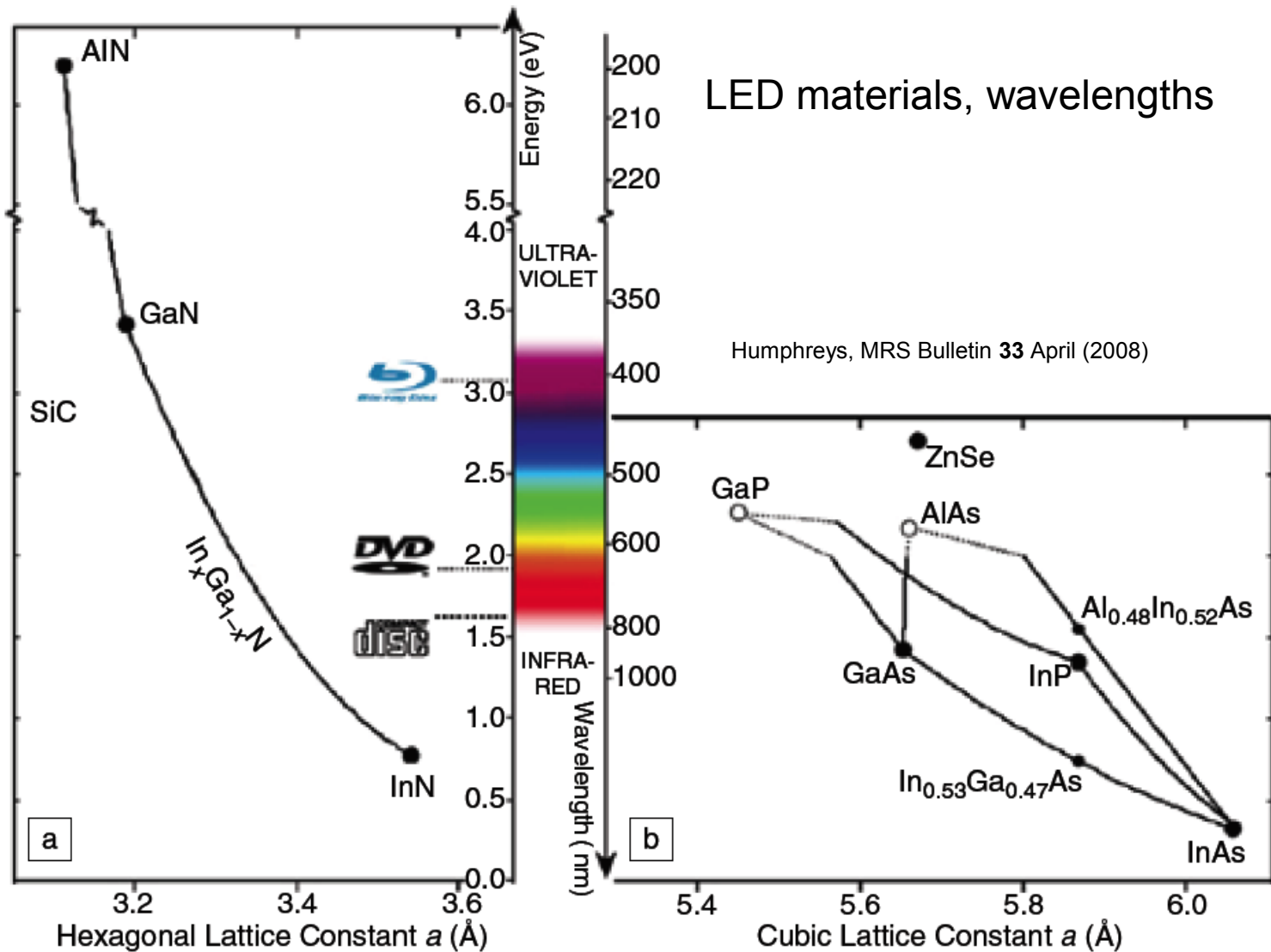
LED (#, color)	λ_{peak} (nm)	Drive-frequency (Hz)
1, Red	700	1000
2, Yellow	600	1153
3, Green	550	1262
4, Blue	470	875
...	-	-



Parallel processing of information from an array of spectral channels encoded in modulated frequency bands

New method: Real-Time Quantum Efficiency measurement system (RTQE)

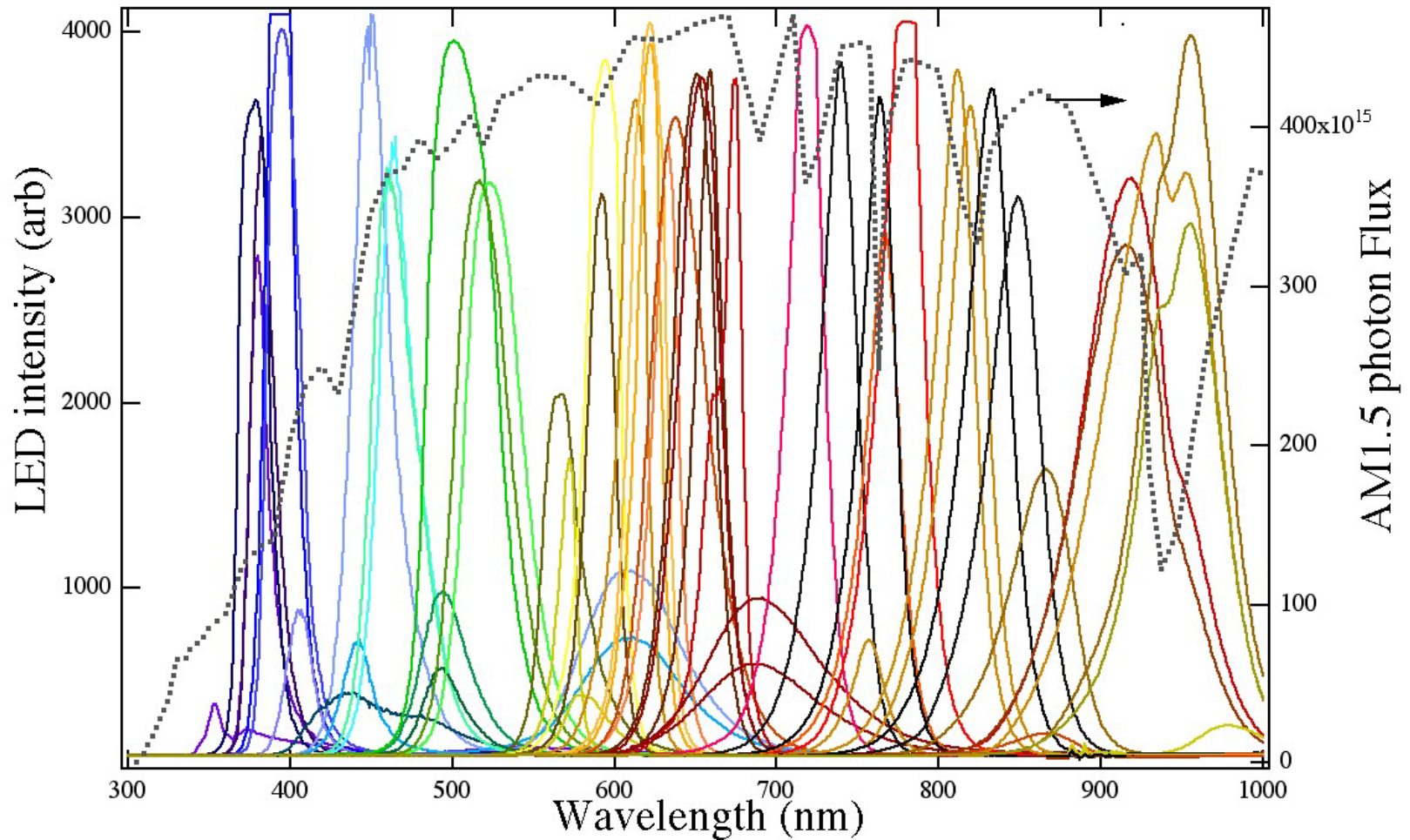
Electronically-Controlled LED light source



New method: Real-Time Quantum Efficiency measurement system (RTQE)

Electronically-Controlled LED light source

58-color LED array (2004)



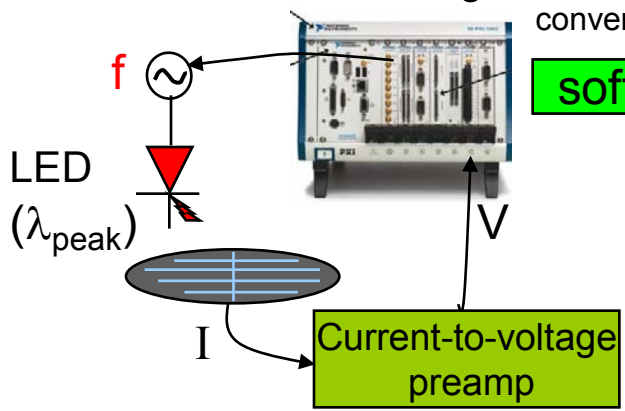
Principle of operation

f, Sine wave drive frequency

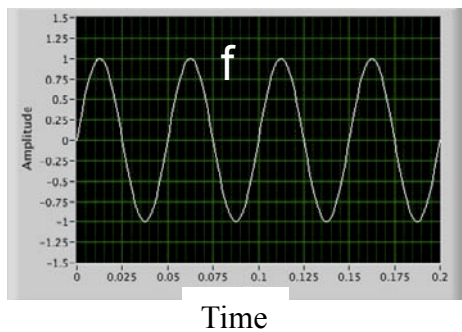
λ , LED emission wavelength

analog-to-digital converter DAQ card

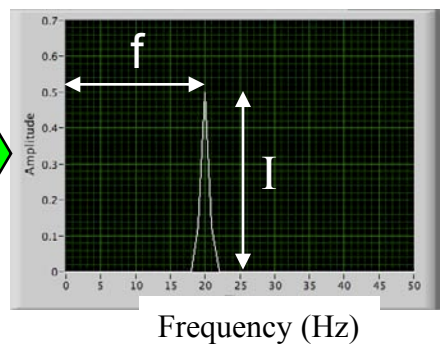
software



voltage vs time



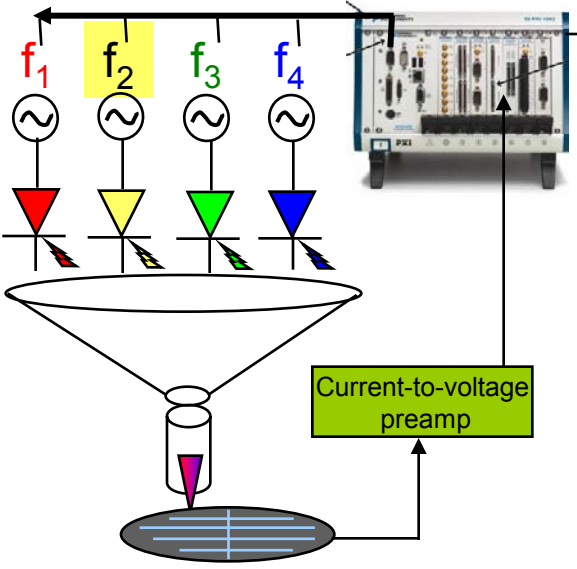
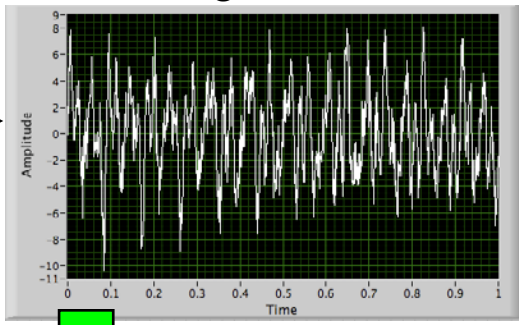
power spectrum



FFT

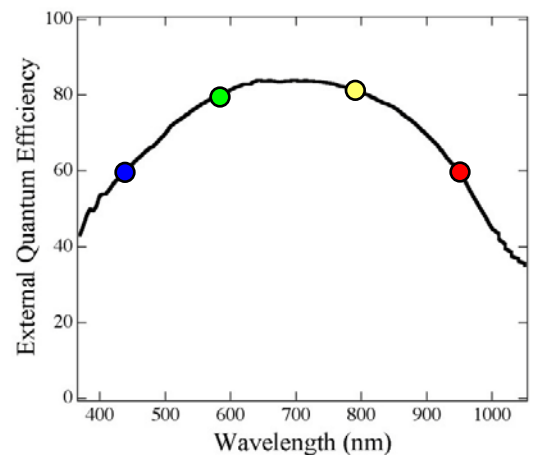
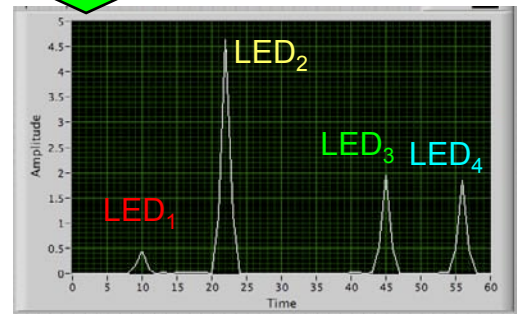
$$f_{\lambda}, QE = K(I(f_{\lambda}))$$

voltage vs time



FFT

power spectrum



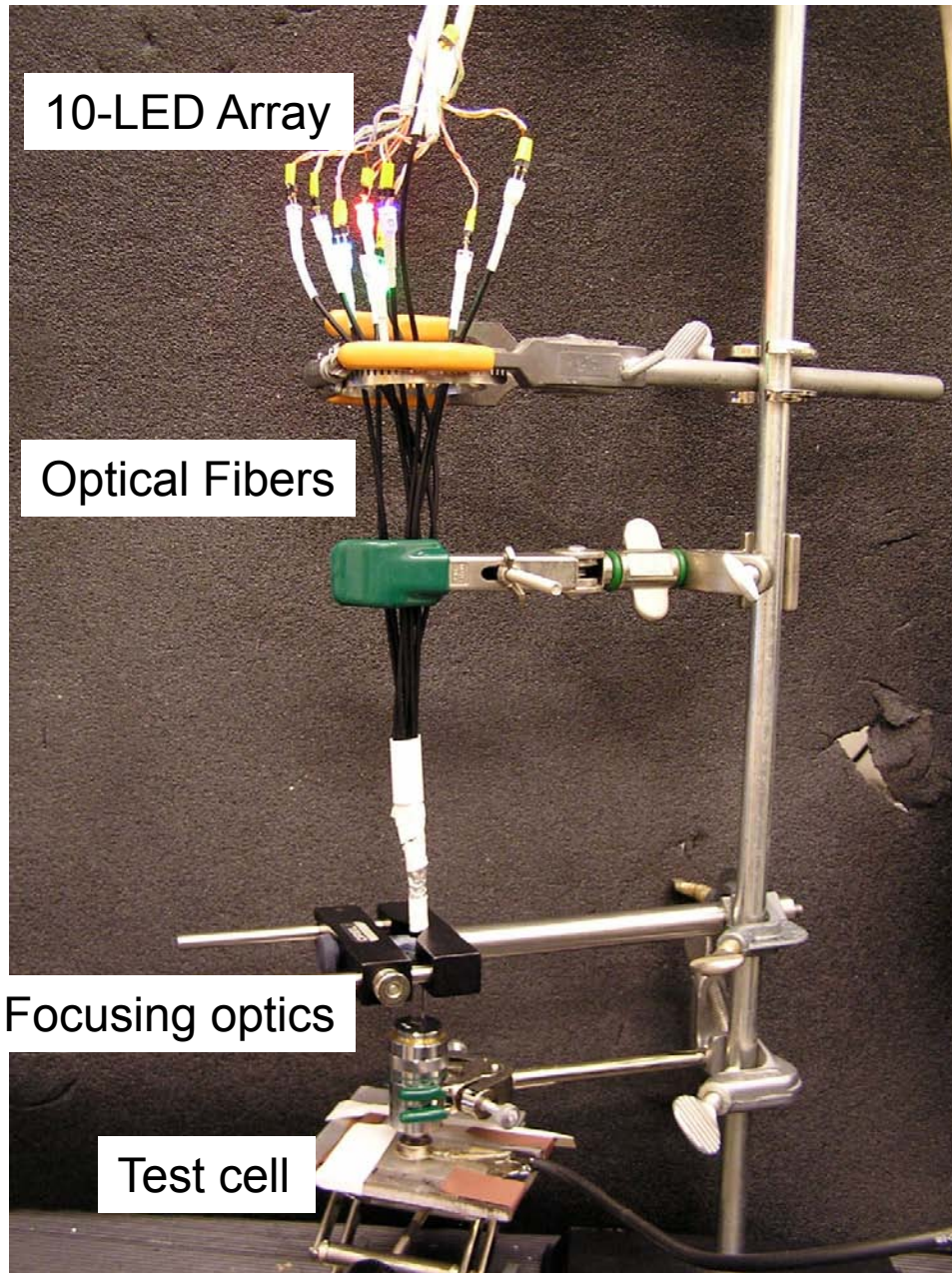
$$f_{\lambda_1}, QE_1 = K_1(I(f_{\lambda_1}))$$

$$f_{\lambda_2}, QE_2 = K_2(I(f_{\lambda_2}))$$

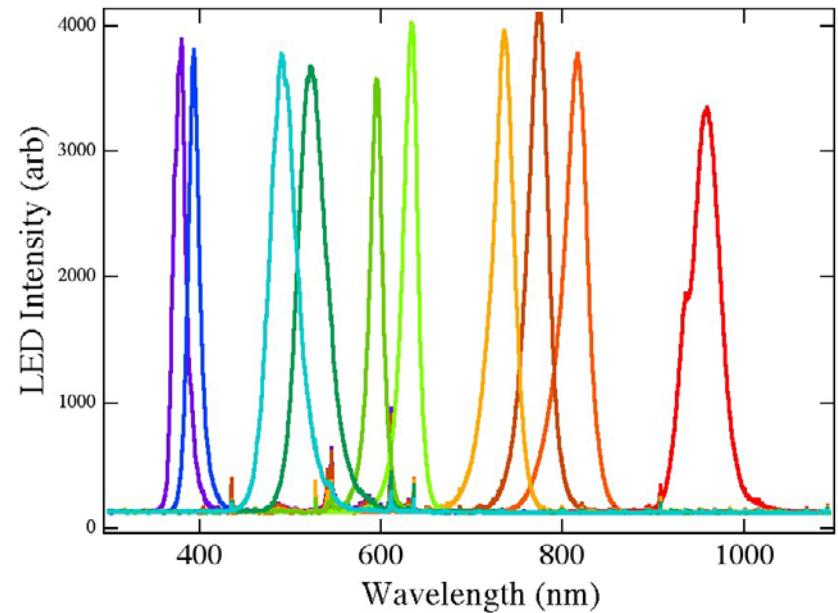
$$f_{\lambda_3}, QE_3 = K_3(I(f_{\lambda_3}))$$

$$f_{\lambda_4}, QE_4 = K_4(I(f_{\lambda_4}))$$

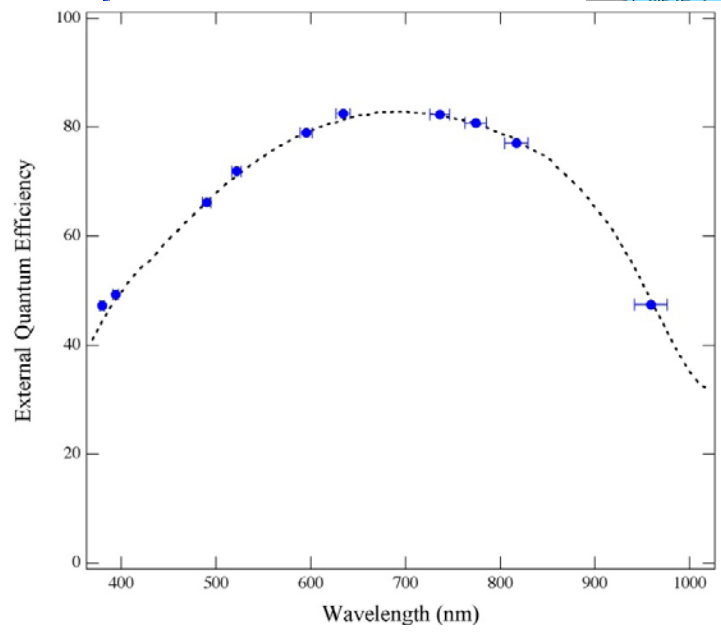
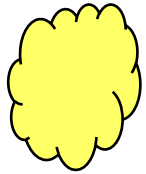
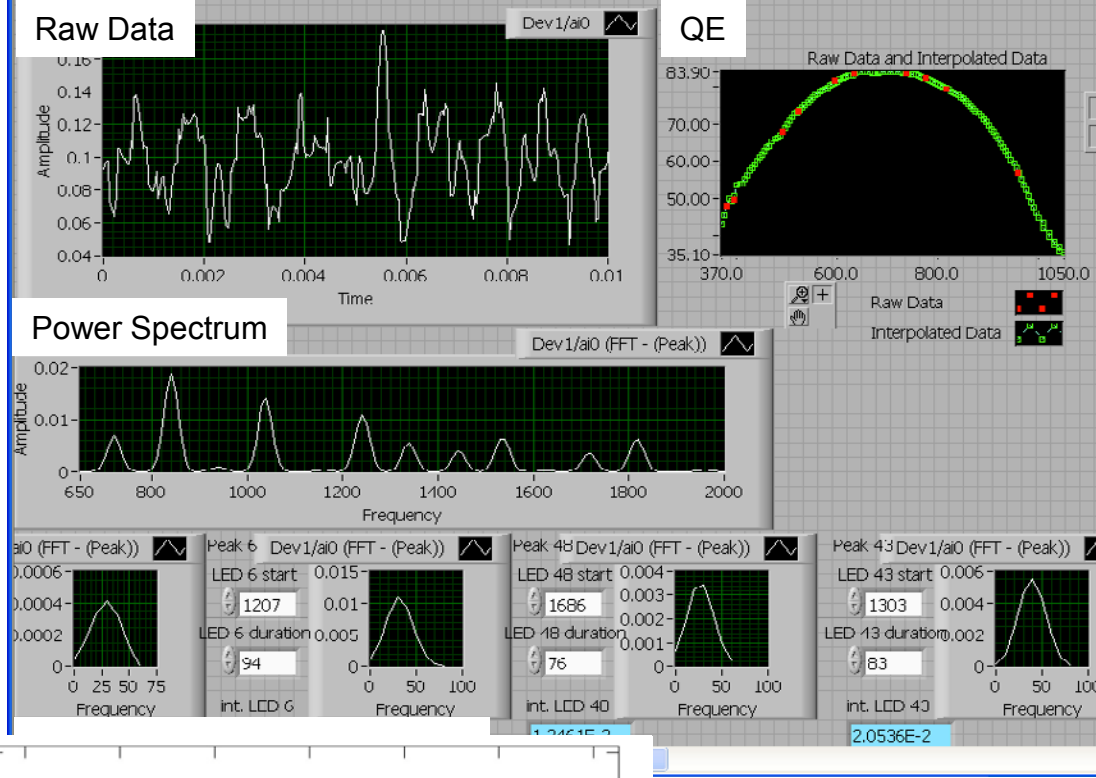
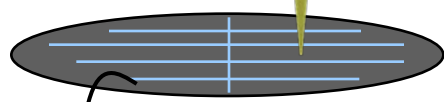
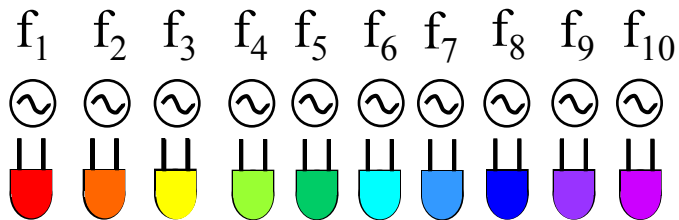
Proof of concept: 10-LED Real-Time QE system prototype



10 LEDs were chosen to span the Spectral response range of C-Si.



10-LED array prototype



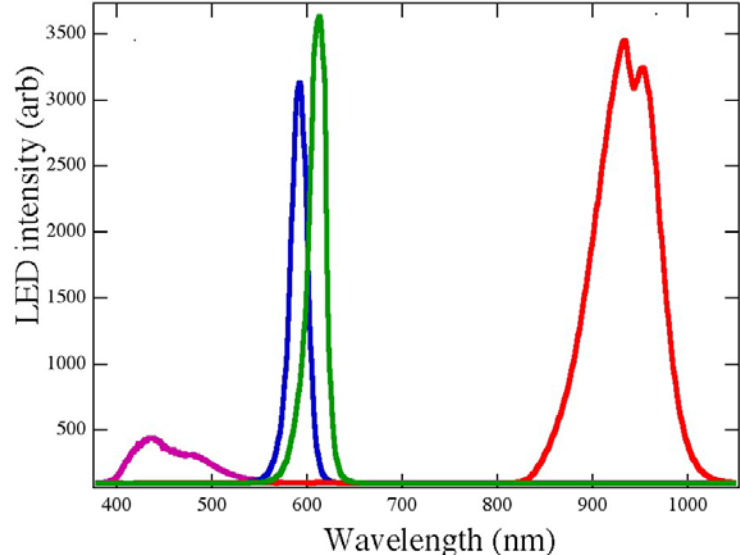
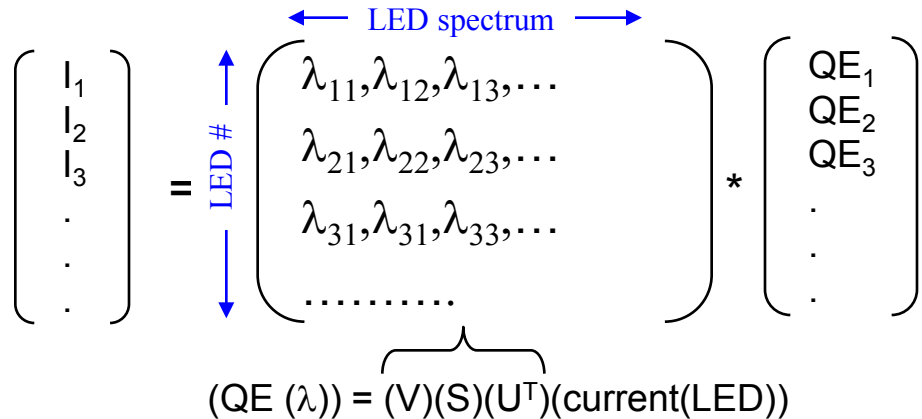
LED QE (real-time)
Standard QE (20 mins)

Technical Considerations:

- 1) LED emission: Spectral width, Asymmetric spectra, Spectral overlap
- Calibration accounts for LED spectra using Singular Value Decomposition mathematics

Singular Value Decomposition (SVD)
 "least-squares-fit" for matrices

Current (LED) = Illumination (LED,λ) * QE(λ)



- 2) LED drive signal: sinusoidal LED emission, non-multiple drive frequencies.
 high data acquisition < drive frequency < 1/response time

- 3) Data acquisition rate: 2x highest LED drive frequency (avoid aliasing)

The Real-Time QE system is:

Parallel processing of information
from an array of spectral channels
encoded in modulated frequency bands

- fast
- inexpensive
- all solid-state
- robust

- Replace traditional lab-based QE systems

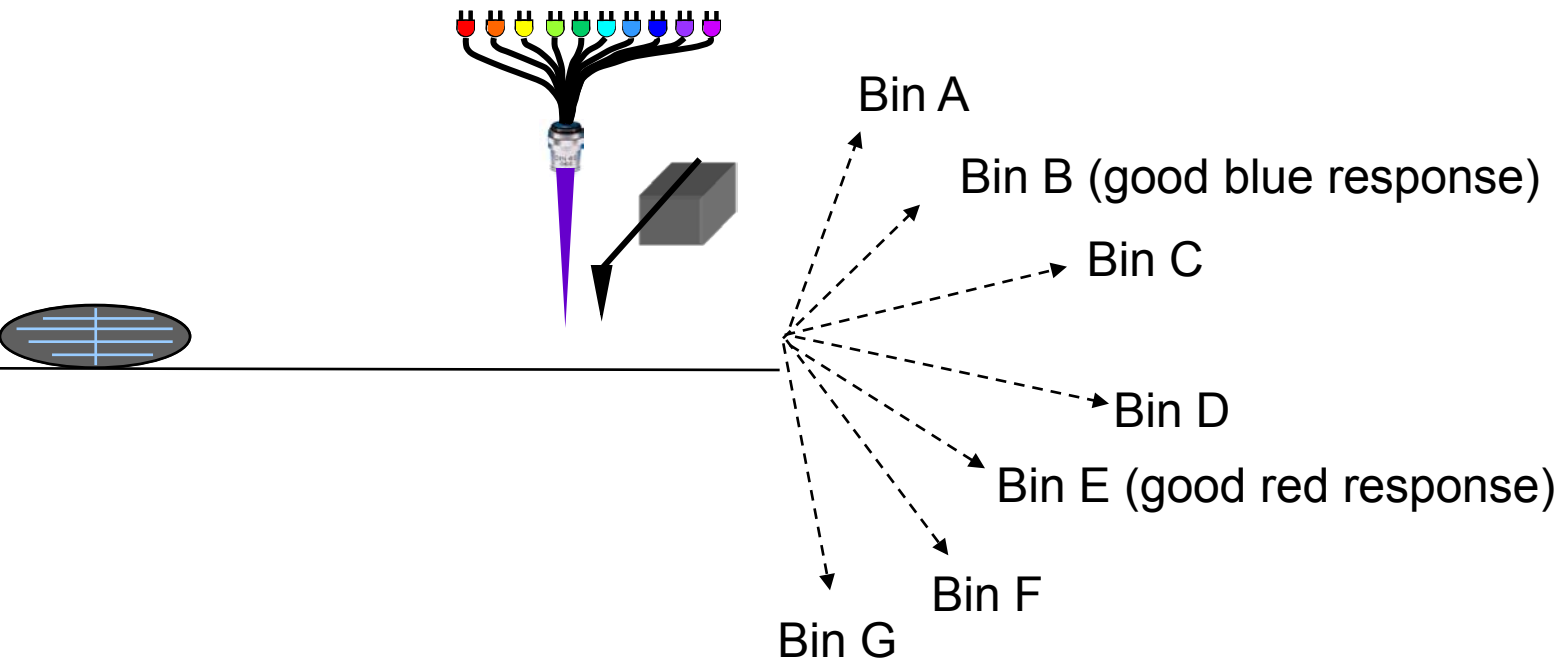
Expanded Applications

- In-line diagnostics
- Spatial QE mapping
- Multi-junction QE measurements

In-line QE for solar cell manufacturing

Benefits:

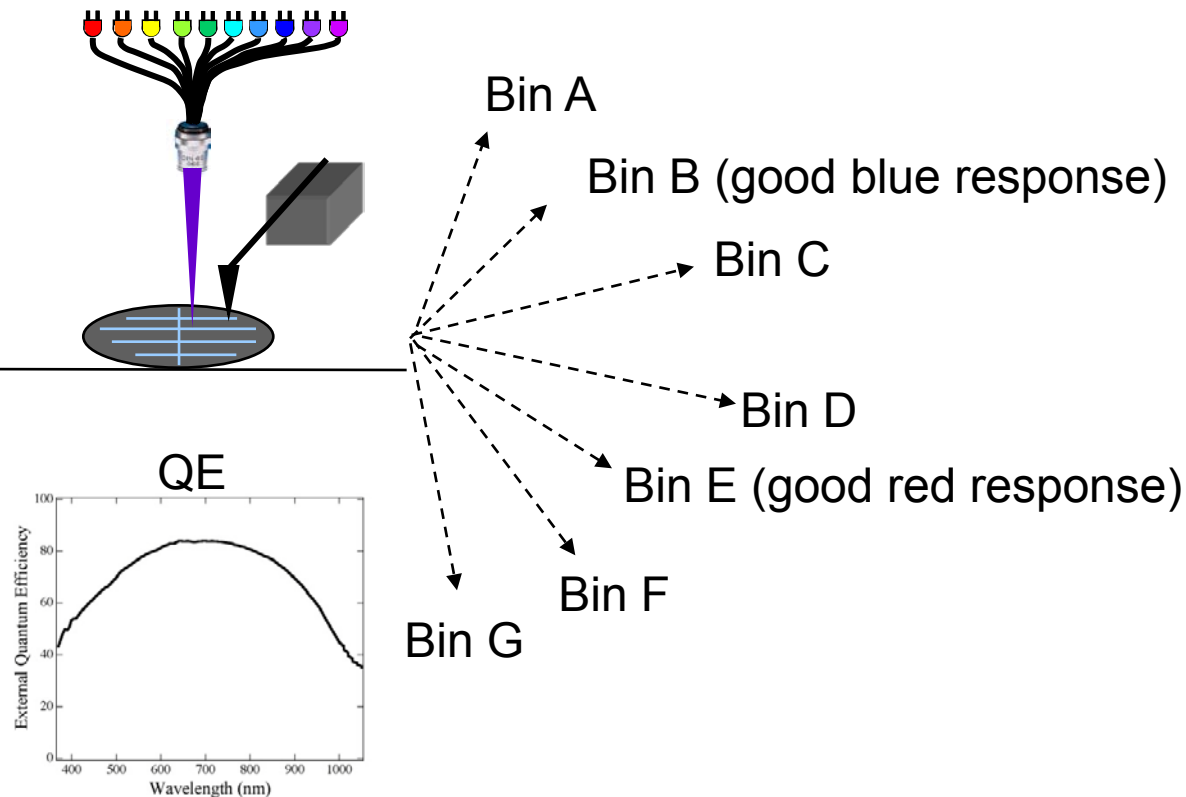
- In-line diagnostics for process control
- Device physics feedback
- Spectral-matching cell binning to maximize module KW-hr output



In-line QE for solar cell manufacturing

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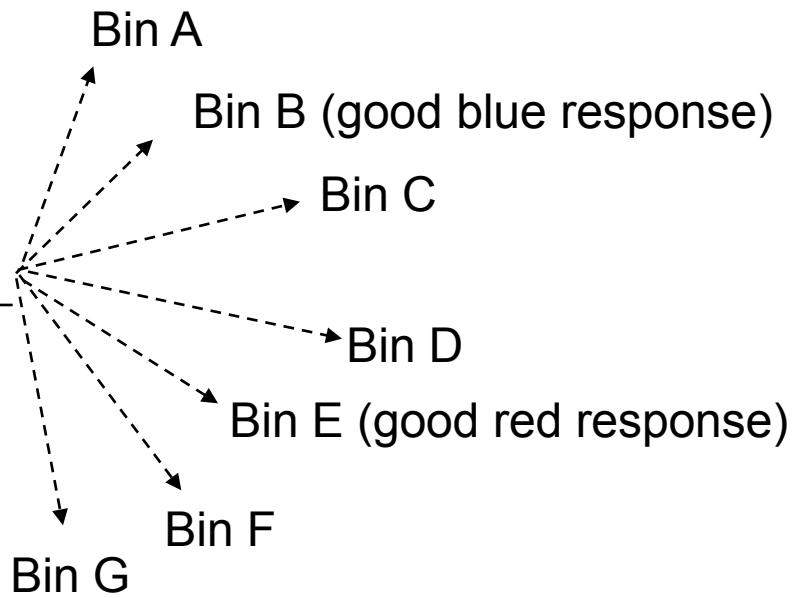
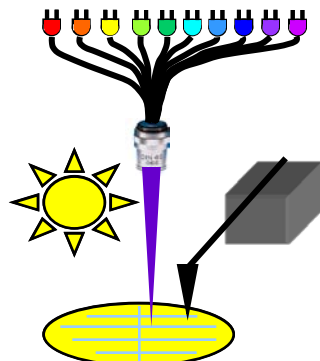
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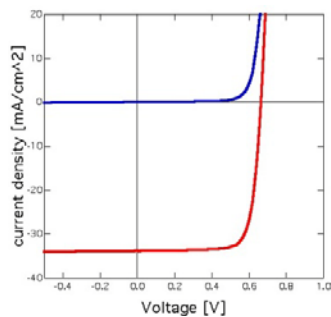
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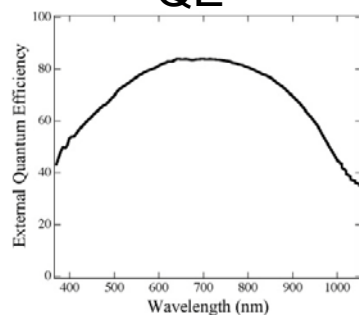
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JV



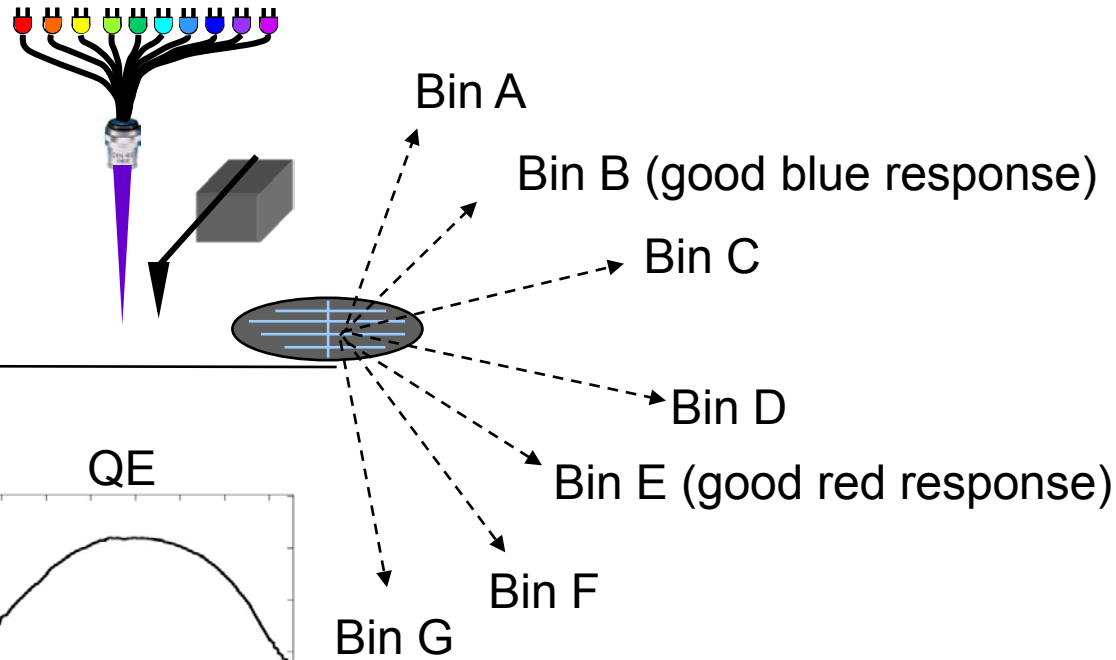
QE



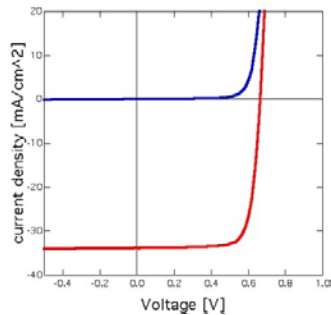
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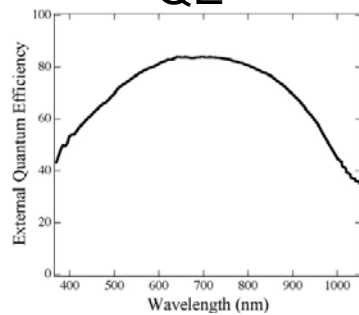
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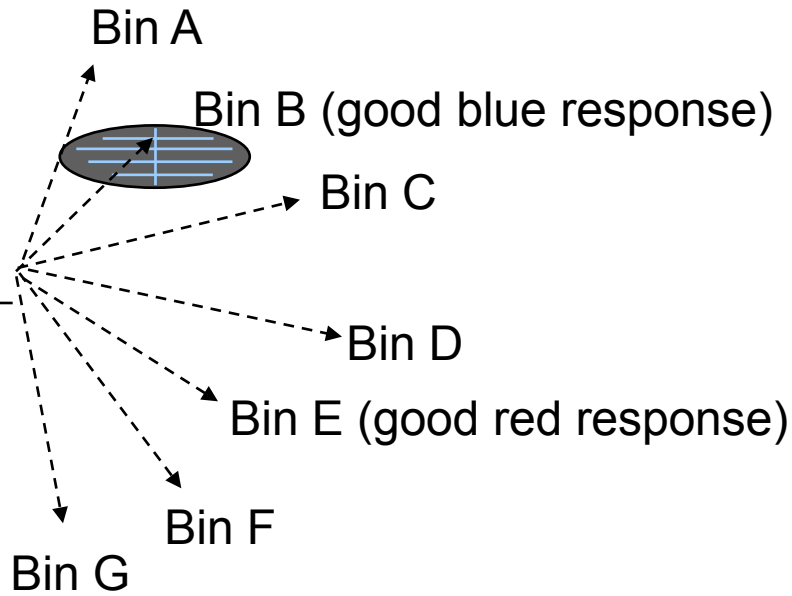
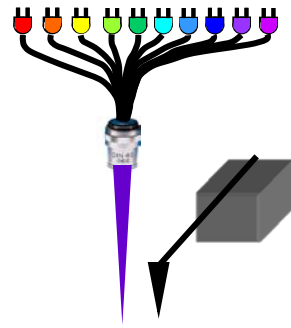
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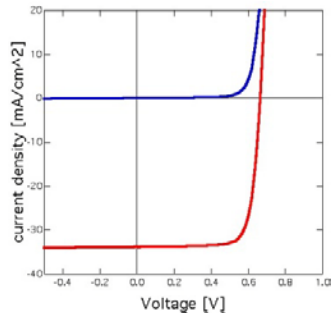
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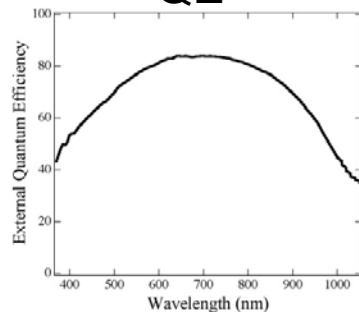
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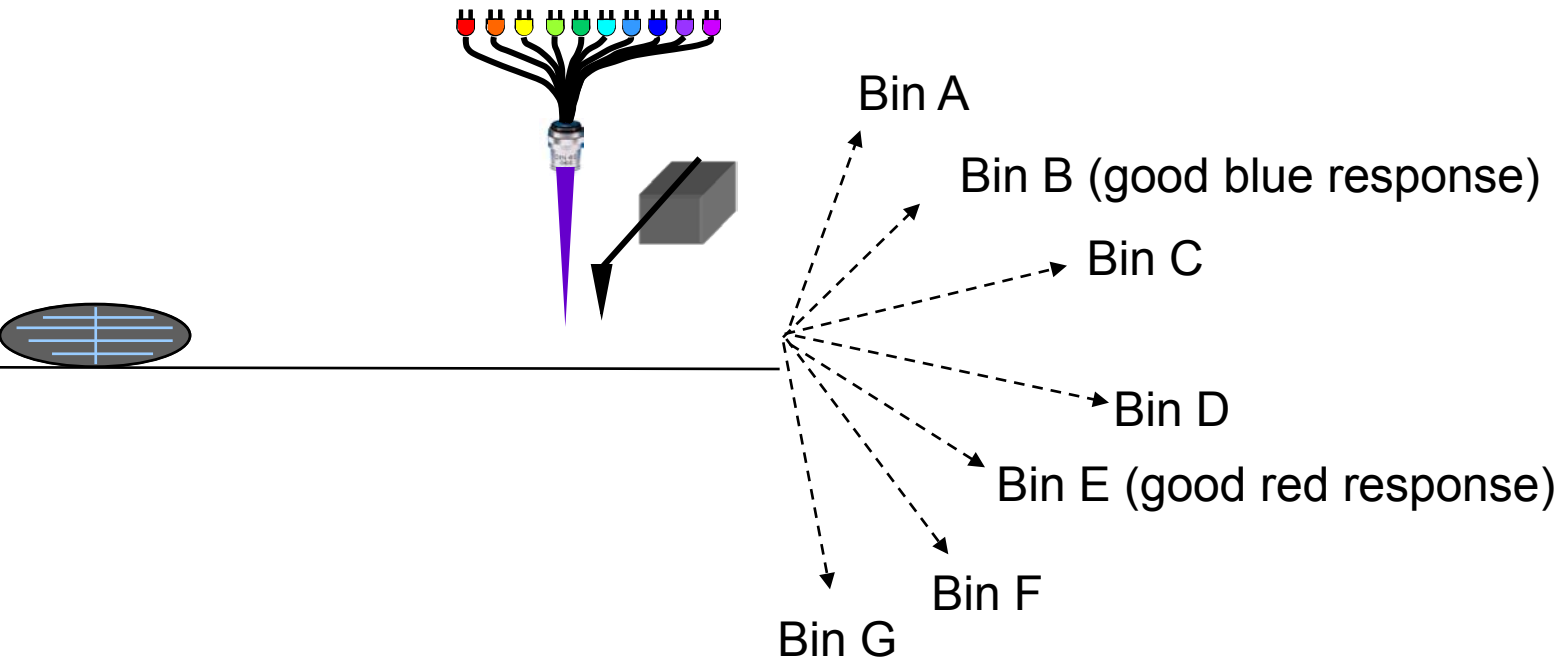
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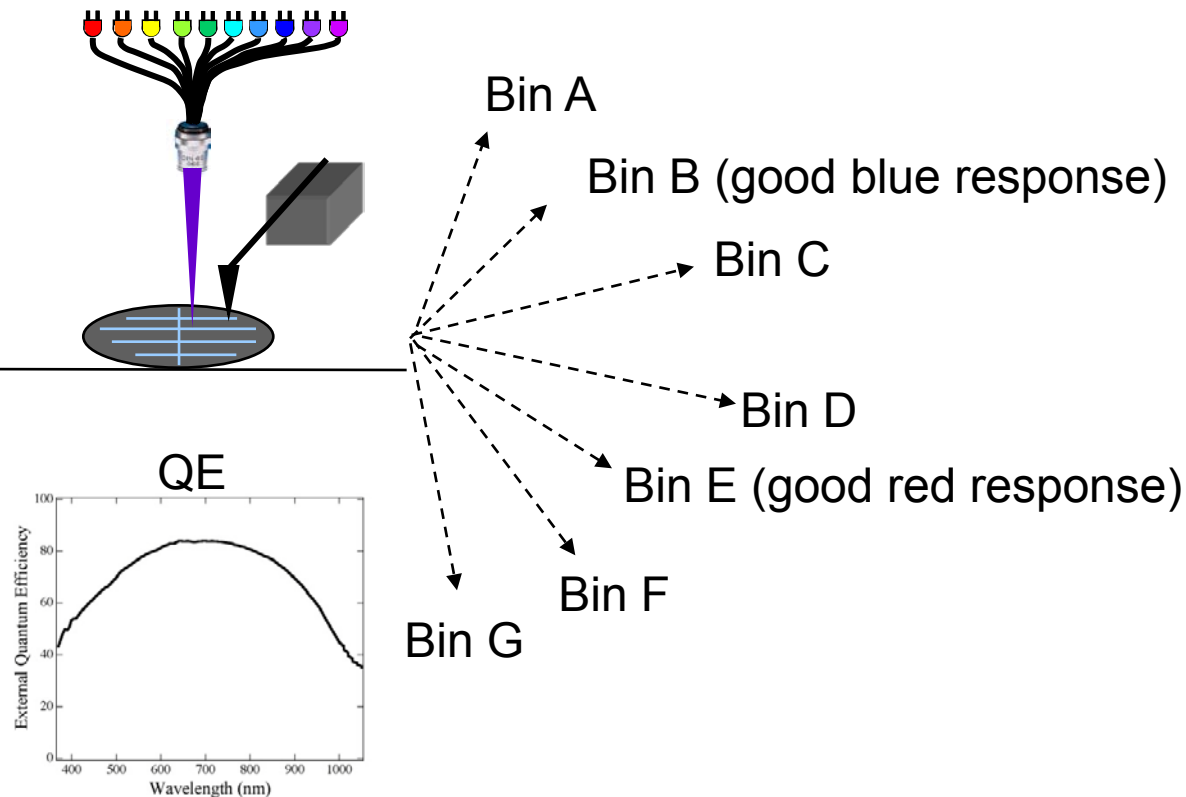
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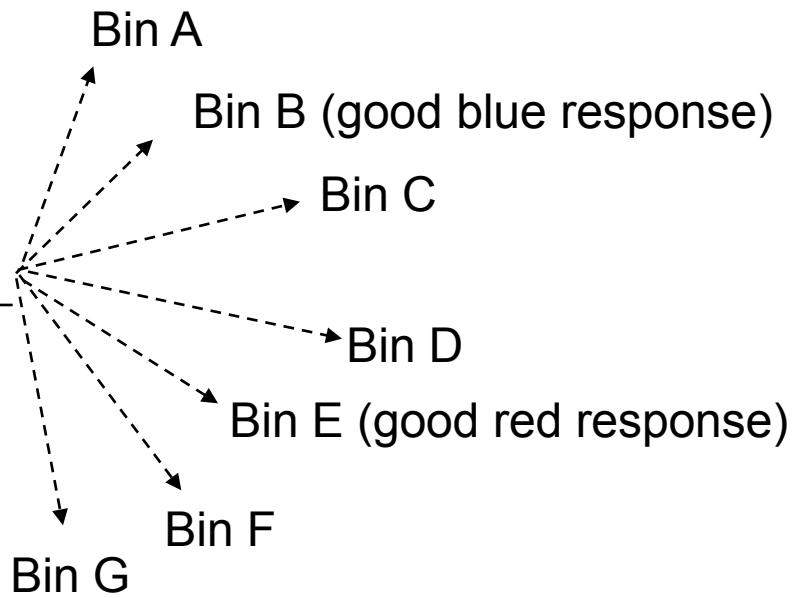
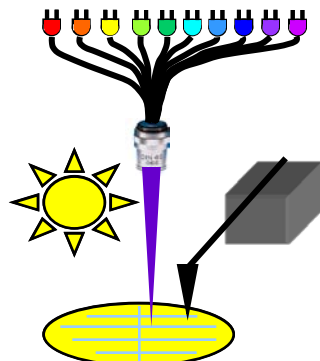
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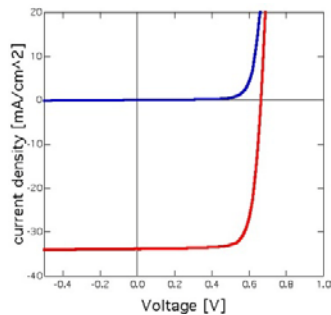
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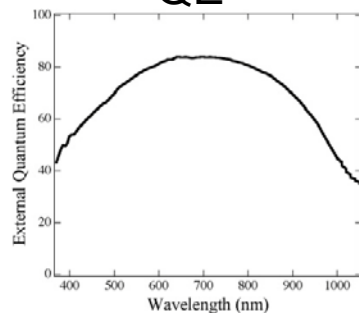
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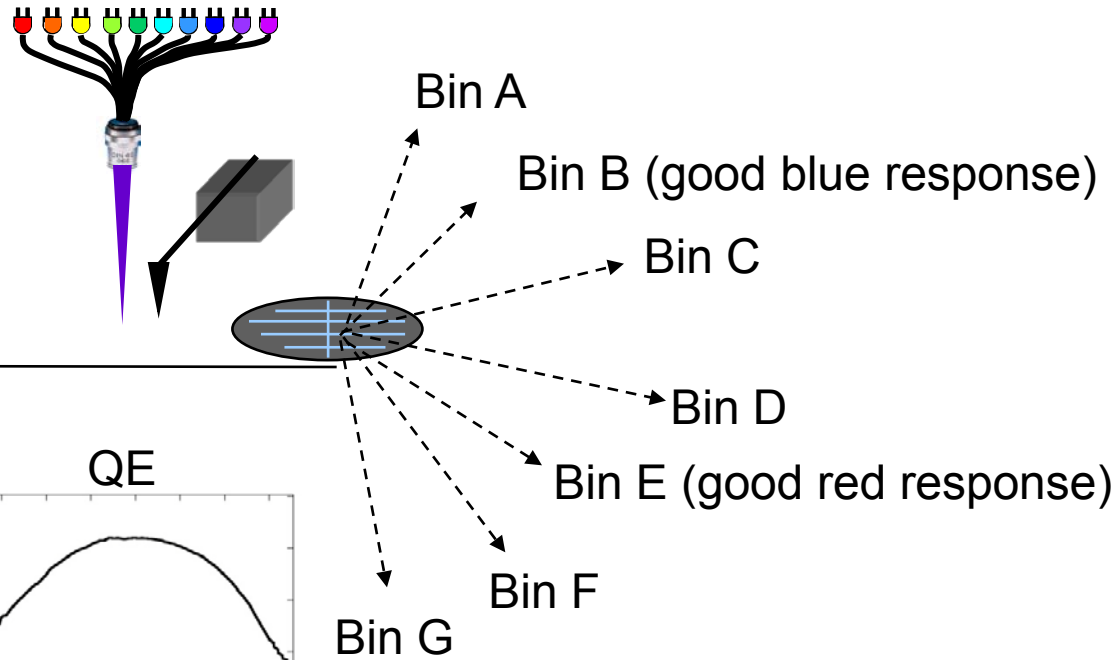
QE



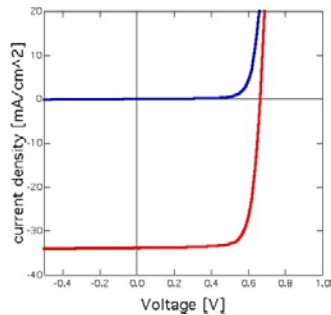
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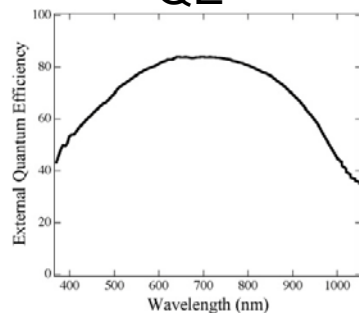
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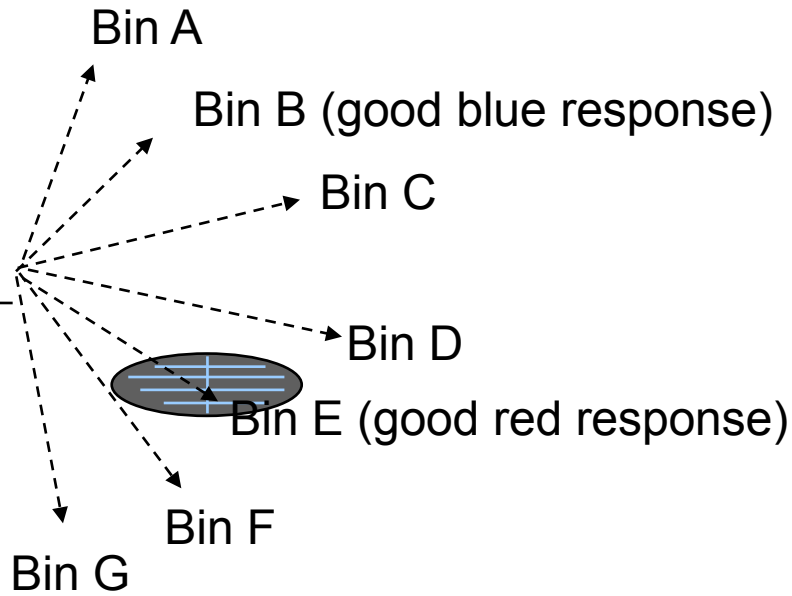
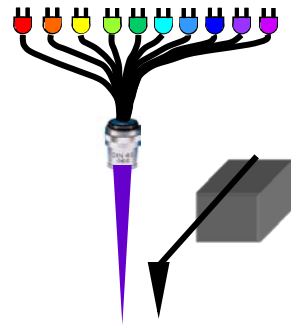
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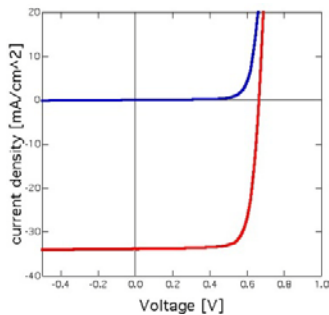
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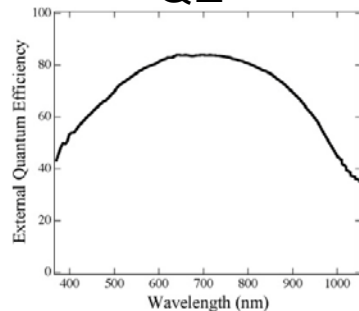
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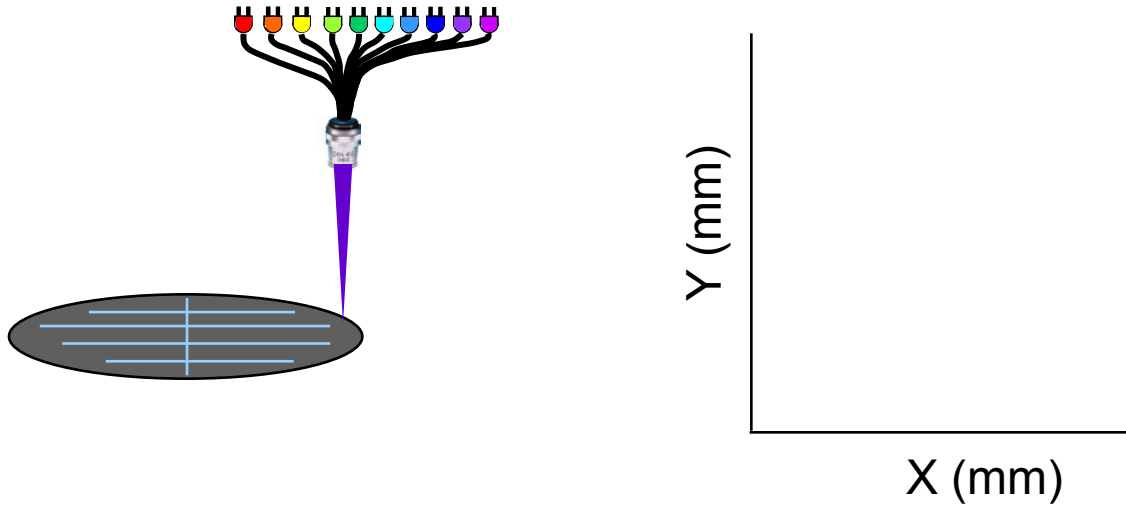
JV



QE

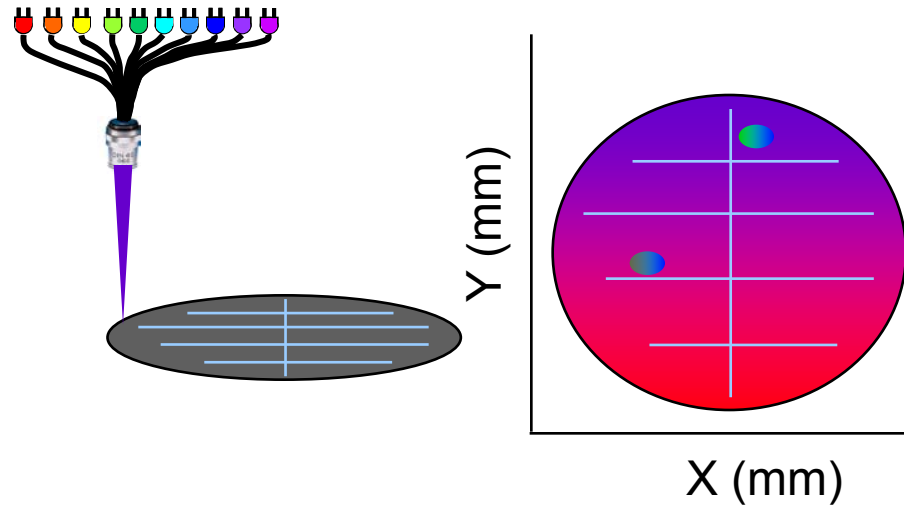


Spatial spectral-response Mapping (cells, modules)



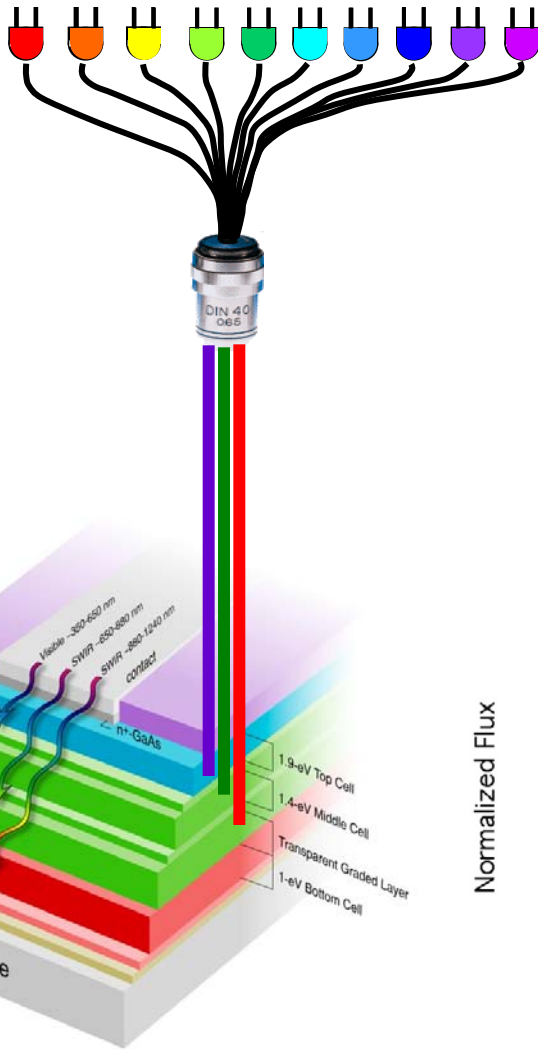
Spatial spectral-response Mapping (cells, modules)

Cell and module uniformity
Defects
Process control

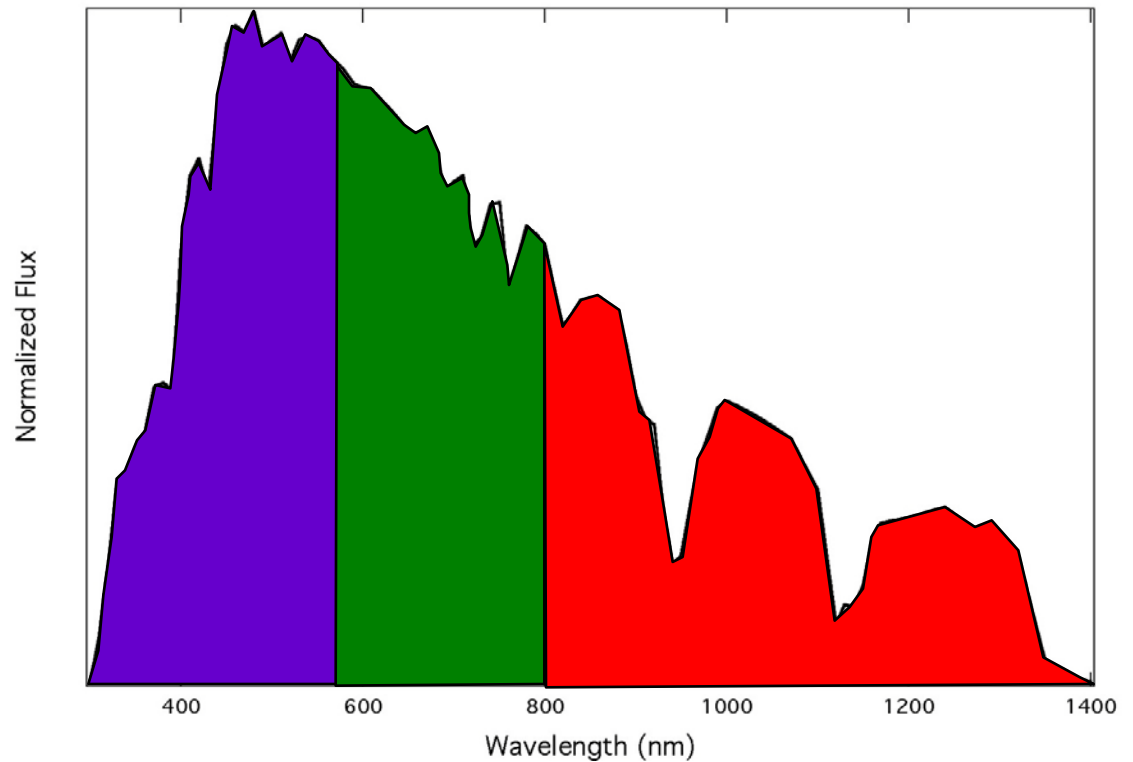


Electronic control of light spectrum

Multi-junction solar cell QE measurements



- RTQE measurement on subcell under test
- Light bias other subcells to allow transport



Real Time Quantum Efficiency Technique

- Electronically controlled full-spectrum LED light source
- Parallel data processing
- Simple, robust, “inexpensive”, solid-state, FAST (~1000 vs 1 QE Measurement during this talk)

Expanded Applications

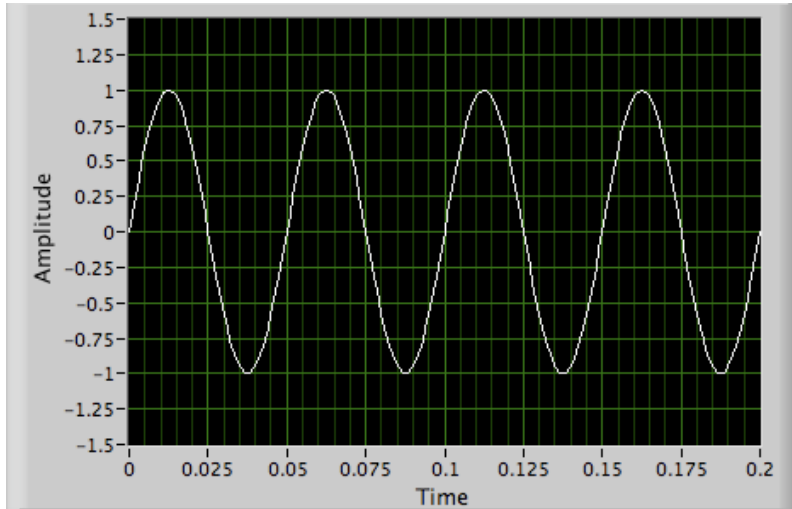
- Industrial In-line diagnostics, spectral-matching cell sorting
- Spatial spectral response mapping
- Electronic filtering – tandem solar cell QE measurements
- Technique applicable to other spectroscopy techniques

Further information:

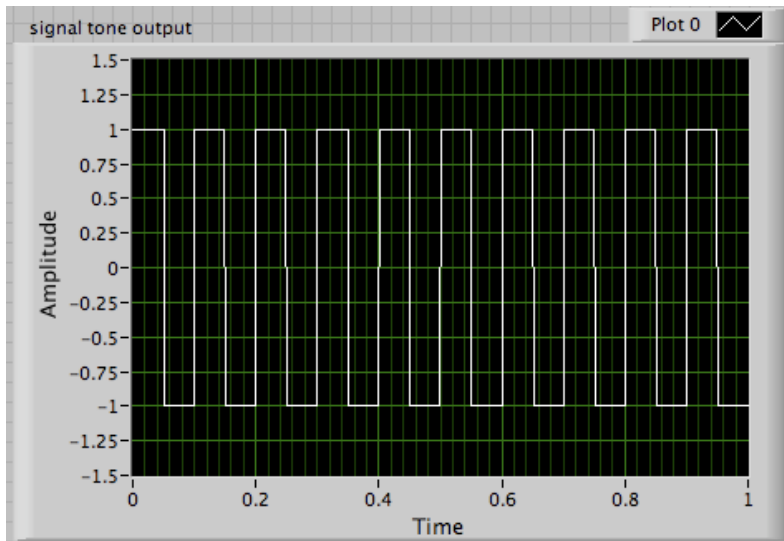
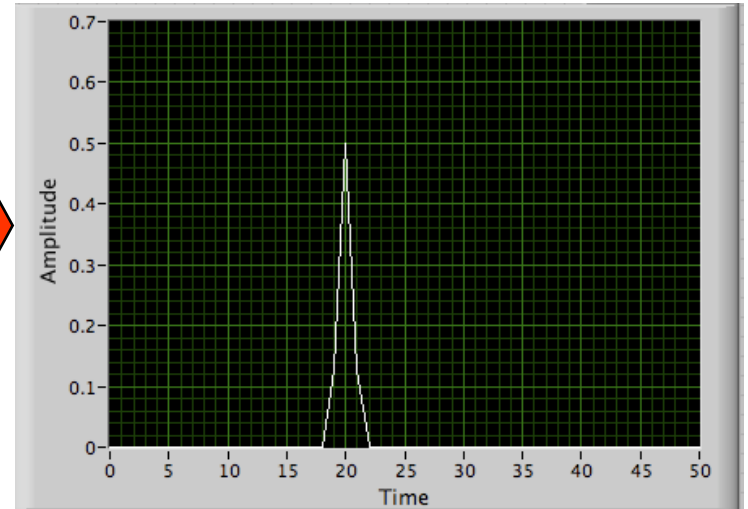
Technical: david_young@nrel.gov

Technology Licensing: david_christensen@nrel.gov

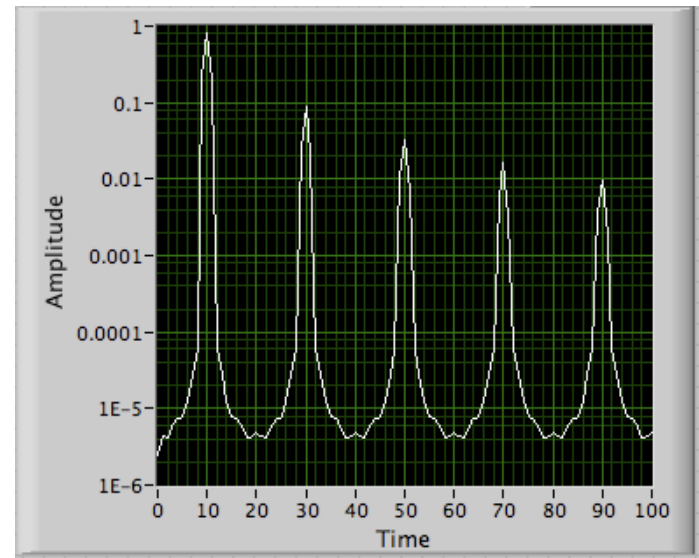
Pure sine wave drive voltage:



FFT



FFT



No multiple frequencies

fast data acquisition rate $<$ Drive frequencies $<$ 1/minority life time, acquisition/2

LED spectral width

